

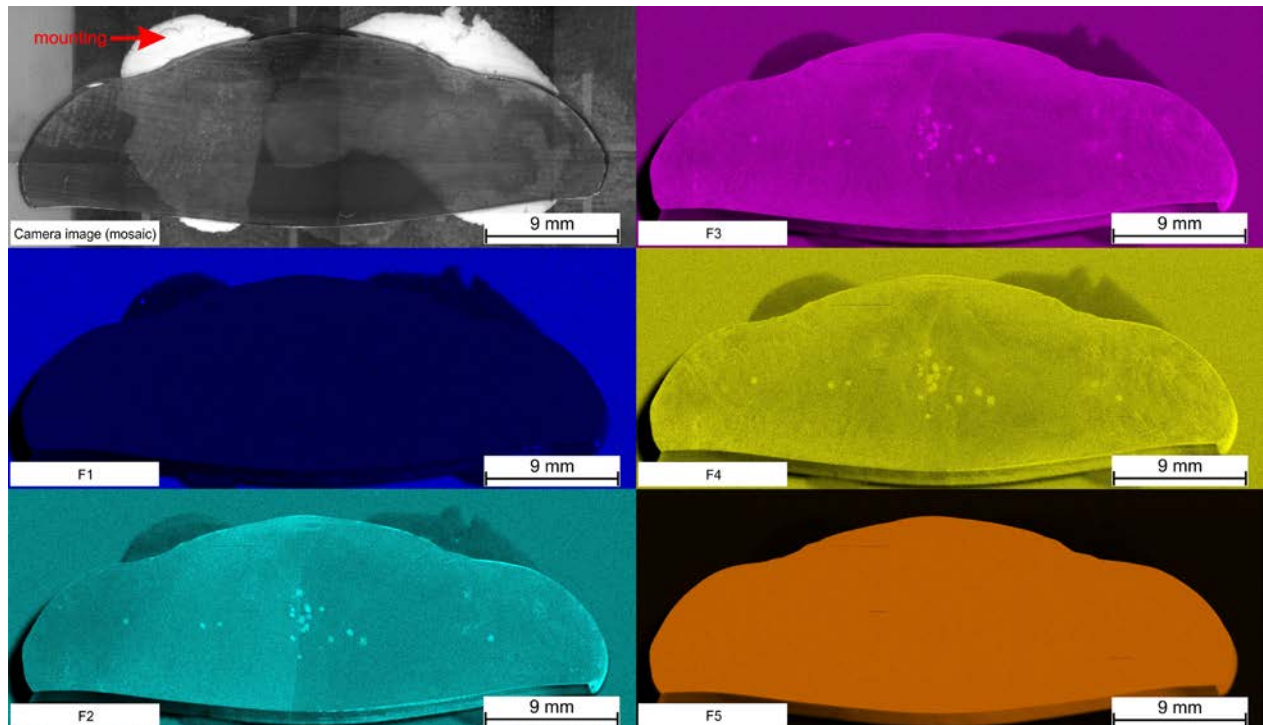
Microstructural investigations of SrTiO₃ single crystals and polysilicon using a powerful new XRD surface mapping technique

Christo Gugushev^{a,*}, Roald Tagle^b, Uta Juda^a, Albert Kwasniewski^a

^a Leibniz Institute for Crystal Growth, Max-Born-Strasse 2, 12489 Berlin, Germany.

^b Bruker Nano GmbH, Am Studio 2D, 12489 Berlin, Germany.

Supplementary I



Supplementary II



Supplementary III

